Chadwin D Young

Chadwin D. Young received the B.S. degree in electrical engineering from the University of Texas, Austin, in 1996 and the M.S. and Ph.D. degrees from the North Carolina State University, Raleigh, in 1998 and 2004, respectively. His Ph.D. dissertation was on high-κ gate stacks. Since 2001, he has been with SEMATECH Inc., Austin, where he is currently a Project Engineer working on electrical characterization and reliability methodologies for the evaluation of high-κ gate stacks. Dr. Young is currently a Guest Editor for IEEE TRANSACTIONS ON DEVICE and MATERIALS RELIABILITY.

Steven Weinzierl

Steven Weinzierl received his A.B. in Physics and Computer Science from Vassar College, and the Ph.D. from Cornell University. Since that time he has specialized in contact and non-contact electrical characterization of semiconductor and dielectric materials, holding key technical and marketing positions at Solid State Measurements, KLA-Tencor, and Keithley Instruments. He specializes in the electrical and optical measurements for process development and production process control, with particular emphasis on advanced gate materials. Dr. Weinzierl is member of IEEE and ECS, has over 20 journal and conference publications, and 1 patent.

SK Cheong

SK Cheong is involved in designing and building many testers for low level measurement in a major part of his career. With his experience in Operations and Research & Development, he is aware of the unique test requirements for each function and will generally give interesting solutions.

SK currently resides in Singapore providing Application Support for South-East Asia. He has a patent pending to his name.